


<b>Search Notes</b>  	<b>Application/Control No.</b>  1059498410594984	<b>Applicant(s)/Patent Under Reexamination</b>  MAJIMA, TAICHIMAJIMA, TAICHI
	<b>Examiner</b>  Mujtaba Chaudry/Mujtaba Chaudry	<b>Art Unit</b>  21122611

SEARCHED			
Class	Subclass	Date	Examiner
714	774	5/18/2010	MC
375	275	5/18/2010	MC
714714	776774	5/18/2010/5/18/2010	MCMC
375	275	5/18/2010	MC
714	776	5/18/2010	MC

SEARCH NOTES		
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EAST DATABASE	5/18/2010	MC
USPATS	5/18/2010	MC
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EPO	5/18/2010	MC
JPO	5/18/2010	MC
DERWANT	5/18/2010	MC
IBM-TDB	5/18/2010	MC
CROSSED ALL RELATED APPS	5/18/2010	MC
GOOGLE/NPL/IEEE EAST DATABASE	5/18/2010/5/18/2010	MCMC
USPATS	5/18/2010	MC
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JPO	5/18/2010	MC
DERWANT	5/18/2010	MC
IBM-TDB	5/18/2010	MC
CROSSED ALL RELATED APPS	5/18/2010	MC
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INTERFERENCE SEARCH			
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Primary Examiner, Art Unit 2112

**INTERFERENCE SEARCH**

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